# NXP PSMN1R4-30YLD MOSFET datasheet

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Logic level gate drive N-channel enhancement mode MOSFET in LFPAK56 package. NextPowerS3 portfolio utilising NXP's unique "SchottkyPlus" technology delivers high efficiency, low spiking performance usually associated with MOSFETs with an integrated Schottky or Schottky-like diode but without problematic high leakage current. NextPowerS3 is particularly suited to high efficiency applications at high switching frequencies.

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N-channel 30 V, 1.4 mΩ logic level MOSFET in LFPAK56 using NextPowerS3 Technology

3 March 2014

**Preliminary data sheet** 

### 1. General description

Logic level gate drive N-channel enhancement mode MOSFET in LFPAK56 package. NextPowerS3 portfolio utilising NXP's unique "SchottkyPlus" technology delivers high efficiency, low spiking performance usually associated with MOSFETs with an integrated Schottky or Schottky-like diode but without problematic high leakage current. NextPowerS3 is particularly suited to high efficiency applications at high switching frequencies.

### 2. Features and benefits

- Ultra low Q<sub>G</sub>, Q<sub>GD</sub> and Q<sub>OSS</sub> for high system efficiency, especially at higher switching frequencies
- Superfast switching with soft-recovery; s-factor > 1
- Low spiking and ringing for low EMI designs
- Unique "SchottkyPlus" technology; Schottky-like performance with < 1 µA leakage at 25 °C
- Optimised for 4.5 V gate drive
- Low parasitic inductance and resistance
- High reliability clip bonded and solder die attach Power SO8 package; no glue, no wire bonds, qualified to 175 °C
- Wave solderable; exposed leads for optimal visual solder inspection

### 3. Applications

- On-board DC-to-DC solutions for server and telecommunications
- Secondary-side synchronous rectification in telecommunication applications
- Voltage regulator modules (VRM)
- Point-of-Load (POL) modules
- Power delivery for V-core, ASIC, DDR, GPU, VGA and system components
- Brushed and brushless motor control
- Power OR-ing

### 4. Quick reference data

Table 1. C	Quick reference data						
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V <sub>DS</sub>	drain-source voltage	25 °C ≤ T <sub>j</sub> ≤ 175 °C		-	-	30	V
I <sub>D</sub>	drain current	T <sub>mb</sub> = 25 °C; V <sub>GS</sub> = 10 V; <u>Fig. 2</u>	[1]	-	-	100	А
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; <u>Fig. 1</u>		-	-	166	W





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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Tj	junction temperature		-55	-	175	°C
Static char	acteristics		I			
R <sub>DSon</sub>	drain-source on-state resistance	V <sub>GS</sub> = 4.5 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; Fig. 10	-	1.44	1.85	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; Fig. 10	-	1.11	1.42	mΩ
Dynamic cl	haracteristics		l			
Q <sub>GD</sub>	gate-drain charge	V <sub>GS</sub> = 4.5 V; I <sub>D</sub> = 25 A; V <sub>DS</sub> = 15 V; Fig. 12; Fig. 13	-	8.5	-	nC
Q <sub>G(tot)</sub>	total gate charge	V <sub>GS</sub> = 4.5 V; I <sub>D</sub> = 25 A; V <sub>DS</sub> = 15 V; Fig. 12; Fig. 13	-	27.6	-	nC
Source-dra	in diode		I			
S	softness factor	$I_{S} = 25 \text{ A}; V_{GS} = 0 \text{ V}; \text{ dI}_{S}/\text{dt} = -100 \text{ A}/\mu\text{s};$ $V_{DS} = 15 \text{ V}; \frac{\text{Fig. 16}}{1000}$	-	0.99	-	

[1] Continuous current is limited by package.

#### **Pinning information** 5.

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source	mb	D
2	S	source		
3	S	source		G-UF4
4	G	gate	មុច្ច	mbb076 S
mb	D	mounting base; connected to drain	1 2 3 4 LFPAK56; Power- SO8 (SOT669)	

#### **Ordering information** 6.

Table 3. Ordering in	formation		
Type number	Package		
	Name	Description	Version
PSMN1R4-30YLD	LFPAK56; Power-SO8	Plastic single-ended surface-mounted package (LFPAK56; Power-SO8); 4 leads	SOT669

PSMN1R4-30YLD

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#### Marking 7.

Table 4. Marking codes	
Type number	Marking code
PSMN1R4-30YLD	1D430L

#### **Limiting values** 8.

#### Table 5. **Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Parameter	Conditions		Min	Max	Unit
drain-source voltage	25 °C ≤ T <sub>j</sub> ≤ 175 °C		-	30	V
drain-gate voltage	25 °C ≤ T <sub>j</sub> ≤ 175 °C; R <sub>GS</sub> = 20 kΩ		-	30	V
gate-source voltage			-20	20	V
total power dissipation	T <sub>mb</sub> = 25 °C; <u>Fig. 1</u>		-	166	W
drain current	V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 25 °C; <u>Fig. 2</u>	[1]	-	100	А
	V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 100 °C; <u>Fig. 2</u>	[1]	-	100	А
peak drain current	pulsed; $t_p \le 10 \ \mu s$ ; $T_{mb} = 25 \ ^{\circ}C$ ; Fig. 3		-	1019	А
storage temperature			-55	175	°C
junction temperature			-55	175	°C
peak soldering temperature			-	260	°C
electrostatic discharge voltage	НВМ		1500	-	V
n diode	·				
source current	T <sub>mb</sub> = 25 °C	[1]	-	100	А
peak source current	pulsed; $t_p \le 10 \ \mu s$ ; $T_{mb} = 25 \ ^{\circ}C$		-	1019	А
uggedness	1				
non-repetitive drain-source avalanche energy	$V_{GS}$ = 10 V; T <sub>j(init)</sub> = 25 °C; I <sub>D</sub> = 25 A; V <sub>sup</sub> ≤ 30 V; R <sub>GS</sub> = 50 Ω; unclamped; t <sub>p</sub> = 1.34 ms	[2]	-	653	mJ
	drain-gate voltage         gate-source voltage         total power dissipation         drain current         peak drain current         storage temperature         junction temperature         peak soldering temperature         electrostatic discharge voltage         n diode         source current         peak source current         non-repetitive drain-source	$\begin{array}{ c c } \hline \label{eq:gate-source-voltage} \\ \hline \mbox{drain-gate voltage} \\ \hline \mbox{gate-source voltage} \\ \hline \mbox{total power dissipation} \\ \hline \mbox{total power dissipation} \\ \hline \mbox{drain current} \\ \hline \mbox{V}_{GS} = 10 \ \mbox{V}; \ \mbox{T}_{mb} = 25 \ \ \mbox{C}; \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \$	$\begin{array}{ c c c } \hline drain-gate voltage & 25 \ ^{\circ}C \leq T_{j} \leq 175 \ ^{\circ}C; R_{GS} = 20 \ k\Omega & \\ \hline gate-source voltage & & \\ \hline total power dissipation & T_{mb} = 25 \ ^{\circ}C; \ Fig. 1 & \\ \hline total power dissipation & \hline T_{mb} = 25 \ ^{\circ}C; \ Fig. 2 & [1] & \\ \hline V_{GS} = 10 \ V; \ T_{mb} = 25 \ ^{\circ}C; \ Fig. 2 & [1] & \\ \hline V_{GS} = 10 \ V; \ T_{mb} = 100 \ ^{\circ}C; \ Fig. 2 & [1] & \\ \hline peak drain current & pulsed; \ t_{p} \leq 10 \ \mu s; \ T_{mb} = 25 \ ^{\circ}C; \ Fig. 3 & \\ \hline storage temperature & & \\ \hline peak soldering temperature & & \\ \hline peak soldering temperature & & \\ \hline electrostatic discharge voltage & HBM & & \\ \hline n \ diode & & \\ \hline source current & \ T_{mb} = 25 \ ^{\circ}C & & \\ \hline uggedness & & \\ \hline uggedness & & \\ \hline non-repetitive drain-source & & \\ \hline V_{GS} = 10 \ V; \ T_{j(init)} = 25 \ ^{\circ}C; \ I_{D} = 25 \ A; \\ V_{sup} \leq 30 \ V; \ R_{GS} = 50 \ \Omega; \ unclamped; \end{array} $	$\begin{array}{ c c  } \hline \mbox{drain-gate voltage} & 25 \ ^{\circ}{\rm C} \le {\rm T_j} \le 175 \ ^{\circ}{\rm C}; \ {\rm R}_{\rm GS} = 20 \ {\rm k}\Omega & - \\ \hline \mbox{gate-source voltage} & -20 \\ \hline \mbox{total power dissipation} & {\rm T}_{mb} = 25 \ ^{\circ}{\rm C}; \ {\rm Fig. 1} & - \\ \hline \mbox{drain current} & {\rm V}_{\rm GS} = 10 \ {\rm V}; \ {\rm T}_{mb} = 25 \ ^{\circ}{\rm C}; \ {\rm Fig. 2} & [1] & - \\ \hline \mbox{V}_{\rm GS} = 10 \ {\rm V}; \ {\rm T}_{mb} = 100 \ ^{\circ}{\rm C}; \ {\rm Fig. 2} & [1] & - \\ \hline \mbox{V}_{\rm GS} = 10 \ {\rm V}; \ {\rm T}_{mb} = 100 \ ^{\circ}{\rm C}; \ {\rm Fig. 2} & [1] & - \\ \hline \mbox{peak drain current} & \mbox{pulsed}; \ {\rm t}_{p} \le 10 \ {\rm \mu s}; \ {\rm T}_{mb} = 25 \ ^{\circ}{\rm C}; \ {\rm Fig. 3} & - \\ \hline \mbox{storage temperature} & \mbox{loc} = 10 \ {\rm \mu s}; \ {\rm T}_{mb} = 25 \ ^{\circ}{\rm C}; \ {\rm Fig. 3} & - \\ \hline \mbox{storage temperature} & \mbox{loc} = -55 \\ \hline \mbox{peak soldering temperature} & \mbox{loc} = -55 \\ \hline \mbox{peak soldering temperature} & \mbox{loc} = -55 \\ \hline \mbox{peak soldering temperature} & \mbox{loc} = -55 \\ \hline \mbox{peak soldering temperature} & \mbox{loc} = -55 \\ \hline \mbox{peak soldering temperature} & \mbox{loc} = -55 \\ \hline \mbox{peak soldering temperature} & \mbox{loc} = -55 \\ \hline \mbox{peak source current} & \mbox{loc} = 25 \ ^{\circ}{\rm C} & \mbox{loc} = -55 \\ \hline \mbox{peak source current} & \mbox{pulsed}; \ \mbox{lp} = 25 \ ^{\circ}{\rm C} & \ \mbox{loc} = -55 \\ \hline \mbox{peak source current} & \mbox{pulsed}; \ \mbox{lp} = 10 \ {\rm \mu s}; \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \$	$\begin{array}{ c c c c } \hline drain-gate voltage & 25 \ ^{\circ}C \leq T_{j} \leq 175 \ ^{\circ}C; \ R_{GS} = 20 \ k\Omega & - & 30 \\ \hline gate-source voltage & -20 & 20 \\ \hline total power dissipation & T_{mb} = 25 \ ^{\circ}C; \ Fig. 1 & - & 166 \\ \hline drain current & V_{GS} = 10 \ V; \ T_{mb} = 25 \ ^{\circ}C; \ Fig. 2 & [1] & - & 100 \\ \hline V_{GS} = 10 \ V; \ T_{mb} = 100 \ ^{\circ}C; \ Fig. 2 & [1] & - & 100 \\ \hline v_{GS} = 10 \ V; \ T_{mb} = 100 \ ^{\circ}C; \ Fig. 2 & [1] & - & 100 \\ \hline peak \ drain \ current & pulsed; \ t_{p} \leq 10 \ \mu s; \ T_{mb} = 25 \ ^{\circ}C; \ Fig. 3 & - & 1019 \\ \hline storage \ temperature & - & 55 & 175 \\ \hline junction \ temperature & - & 55 & 175 \\ \hline peak \ soldering \ temperature & - & 260 \\ \hline electrostatic \ discharge \ voltage & HBM & 1500 & - \\ \hline n \ diode & & & & \\ \hline source \ current & \ T_{mb} = 25 \ ^{\circ}C & [1] & - & 100 \\ \hline peak \ source \ current & \ T_{mb} = 25 \ ^{\circ}C & [1] & - & 100 \\ \hline peak \ source \ current & \ T_{mb} = 25 \ ^{\circ}C & [1] & - & 100 \\ \hline peak \ source \ current & \ T_{mb} = 25 \ ^{\circ}C & [1] & - & 100 \\ \hline peak \ source \ current & \ V_{GS} = 10 \ V; \ T_{mb} = 25 \ ^{\circ}C & [1] & - & 100 \\ \hline peak \ source \ current & \ T_{mb} = 25 \ ^{\circ}C & [1] & - & 100 \\ \hline peak \ source \ current & \ T_{mb} = 25 \ ^{\circ}C & [1] & - & 100 \\ \hline peak \ source \ current & \ V_{GS} = 10 \ V; \ T_{j(init)} = 25 \ ^{\circ}C & [1] & - & 1019 \\ \hline peak \ source \ current & \ pulsed; \ t_{p} \leq 10 \ \mu s; \ T_{mb} = 25 \ ^{\circ}C & [1] & - & 1019 \\ \hline peak \ source \ current & \ V_{GS} = 10 \ V; \ T_{j(init)} = 25 \ ^{\circ}C; \ I_{D} = 25 \ ^{\circ}C; \ $

Continuous current is limited by package. [1]

[2] Protected by 100% test

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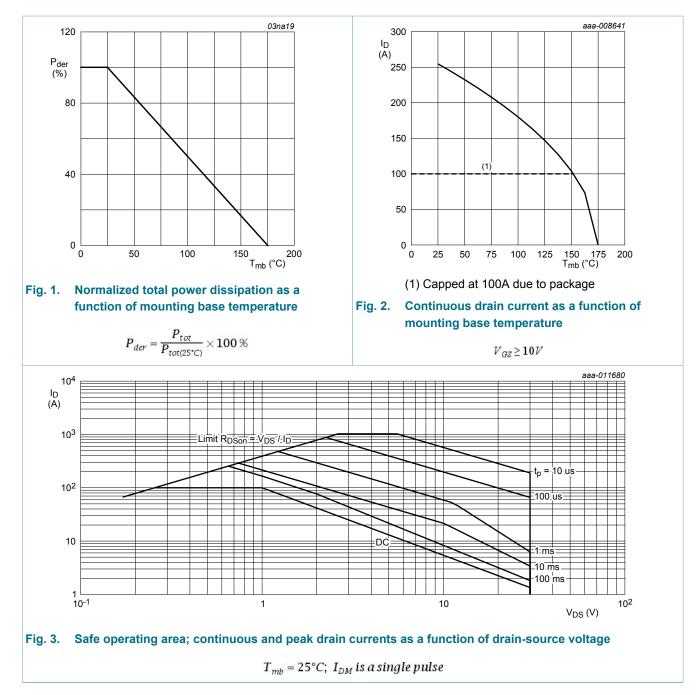
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#### N-channel 30 V, 1.4 mΩ logic level MOSFET in LFPAK56 using NextPowerS3 Technology



### 9. Thermal characteristics

Table 6. TI	hermal characteristics					
Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	Fig. 4	-	0.81	0.9	K/W

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Symbol	Parameter	Conditions		Min	Тур	Мах	Unit
R <sub>th(j-a)</sub>	thermal resistance	<u>Fig. 5</u>		-	50	-	K/W
	from junction to ambient	<u>Fig. 6</u>		-	125	-	K/W
1					aa	aa-008642	
Z <sub>th(j-mb)</sub> (K/W) δ <sup>·=:0</sup> 0:2=							
10 <sup>-1</sup> 0:1=							
10 <sup>-2</sup>	single shot			P		$\overline{\delta} = \frac{t_p}{T}$	
10 <sup>-3</sup> 10 <sup>-6</sup>	10 <sup>-5</sup>	10 <sup>-4</sup> 10 <sup>-3</sup> 10	2	10 <sup>-1</sup>	I →	1 (s)	
ig. 4. Tran	sient thermal impedance	from junction to mounting base as	a function	of puls			
-	a layout for thermal resist ient 1" square pad; FR4 I		out for th t minimur			ce junct	
0. Char	acteristics						
ble 7. Ch	naracteristics						
ymbol	Parameter	Conditions		Min	Тур	Мах	Unit
tatic charac	cteristics						
(BR)DSS	drain-source	$I_D$ = 250 µA; $V_{GS}$ = 0 V; $T_j$ = 25 °C		30	-	-	V
	breakdown voltage	$I_D$ = 250 µA; $V_{GS}$ = 0 V; $T_j$ = -55 °C		27	-	-	V
/ <sub>GS(th)</sub>	gate-source threshold voltage	$I_D$ = 1 mA; $V_{DS}$ = $V_{GS}$ ; $T_j$ = 25 °C		1.2	1.7	2.2	V

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	octeristics	Г				
V <sub>(BR)DSS</sub> drain-source breakdown voltage		$I_D$ = 250 µA; $V_{GS}$ = 0 V; $T_j$ = 25 °C	30	-	-	V
	breakdown voltage	$I_D$ = 250 µA; $V_{GS}$ = 0 V; $T_j$ = -55 °C	27	-	-	V
V <sub>GS(th)</sub>	gate-source threshold voltage	$I_D$ = 1 mA; $V_{DS}$ = $V_{GS}$ ; $T_j$ = 25 °C	1.2	1.7	2.2	V
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#### N-channel 30 V, 1.4 mΩ logic level MOSFET in LFPAK56 using NextPowerS3 Technology

Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
ΔV <sub>GS(th)</sub> /ΔT	gate-source threshold voltage variation with temperature	25 °C ≤ T <sub>j</sub> ≤ 150 °C	-	-4.6	-	mV/K
I <sub>DSS</sub>	drain leakage current	$V_{DS}$ = 24 V; $V_{GS}$ = 0 V; $T_j$ = 25 °C	-	-	1	μA
		V <sub>DS</sub> = 24 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 125 °C	-	1.4	-	μA
I <sub>GSS</sub>	gate leakage current	V <sub>GS</sub> = 16 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	-	100	nA
		$V_{GS}$ = -16 V; $V_{DS}$ = 0 V; $T_j$ = 25 °C	-	-	100	nA
R <sub>DSon</sub>	drain-source on-state resistance	V <sub>GS</sub> = 4.5 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>	-	1.44	1.85	mΩ
		V <sub>GS</sub> = 4.5 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 150 °C; Fig. 11; Fig. 10	-	-	3.05	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; Fig. 10	-	1.11	1.42	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 150 °C; Fig. 11; Fig. 10	-	-	2.34	mΩ
R <sub>G</sub>	gate resistance	f = 1 MHz	-	1.1	-	Ω
Dynamic ch	aracteristics	· · · · ·	I		1	
Q <sub>G(tot)</sub>	total gate charge	I <sub>D</sub> = 25 A; V <sub>DS</sub> = 15 V; V <sub>GS</sub> = 10 V; Fig. 12; Fig. 13	-	54.8	-	nC
		I <sub>D</sub> = 25 A; V <sub>DS</sub> = 15 V; V <sub>GS</sub> = 4.5 V; Fig. 12; Fig. 13	-	27.6	-	nC
		$I_D = 0 A; V_{DS} = 0 V; V_{GS} = 10 V$	-	50.4	-	nC
Q <sub>GS</sub>	gate-source charge	$I_D$ = 25 A; $V_{DS}$ = 15 V; $V_{GS}$ = 4.5 V;	-	7.2	-	nC
Q <sub>GS(th)</sub>	pre-threshold gate- source charge	Fig. 12; Fig. 13	-	3.8	-	nC
$Q_{GS(th-pl)}$	post-threshold gate- source charge		-	3.4	-	nC
Q <sub>GD</sub>	gate-drain charge		-	8.5	-	nC
V <sub>GS(pl)</sub>	gate-source plateau voltage	I <sub>D</sub> = 25 A; V <sub>DS</sub> = 15 V; <u>Fig. 12; Fig. 13</u>	-	2.7	-	V
C <sub>iss</sub>	input capacitance	V <sub>DS</sub> = 15 V; V <sub>GS</sub> = 0 V; f = 1 MHz;	-	3840	-	pF
C <sub>oss</sub>	output capacitance	T <sub>j</sub> = 25 °C; <u>Fig. 14</u>	-	1785	-	pF
C <sub>rss</sub>	reverse transfer capacitance		-	251	-	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS}$ = 15 V; R <sub>L</sub> = 0.6 Ω; V <sub>GS</sub> = 4.5 V;	-	23	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 5 \Omega$	-	28	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	31.5	-	ns
t <sub>f</sub>	fall time		-	20.6	-	ns

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aaa-011682

12 14 V<sub>GS</sub> (V)

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Symbol	Parameter	Conditions		Min	Тур	Мах	Unit
Q <sub>oss</sub>	output charge	V <sub>GS</sub> = 0 V; V <sub>DS</sub> = 15 V; f = 1 MHz; T <sub>j</sub> = 25 °C		-	40	-	nC
Source-dra	iin diode	I			- 1		
V <sub>SD</sub>	source-drain voltage	$I_{S}$ = 25 A; $V_{GS}$ = 0 V; $T_{j}$ = 25 °C; <u>Fig. 15</u>		-	0.79	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_{S}$ = 25 A; dI <sub>S</sub> /dt = -100 A/µs; V <sub>GS</sub> = 0 V;		-	38.6	-	ns
Q <sub>r</sub>	recovered charge	V <sub>DS</sub> = 15 V; <u>Fig. 16</u>	[1]	-	34	-	nC
t <sub>a</sub>	reverse recovery rise time			-	19.4	-	ns
t <sub>b</sub>	reverse recovery fall time			-	19.3	-	ns
S	softness factor	-		-	0.99	-	

16

12

8

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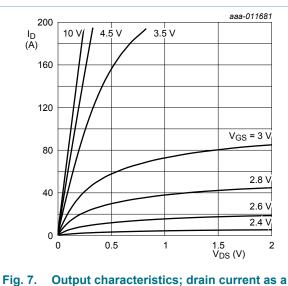
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R<sub>DSon</sub> (mΩ)



[1] includes capacitive recovery

Fig. 8. Drain-source on-state resistance as a function of gate-source voltage; typical values

8

10

 $T_j = 25^{\circ}C$ 

function of drain-source voltage; typical values

 $T_j = 25^{\circ}C; \ I_D = 25A$ 

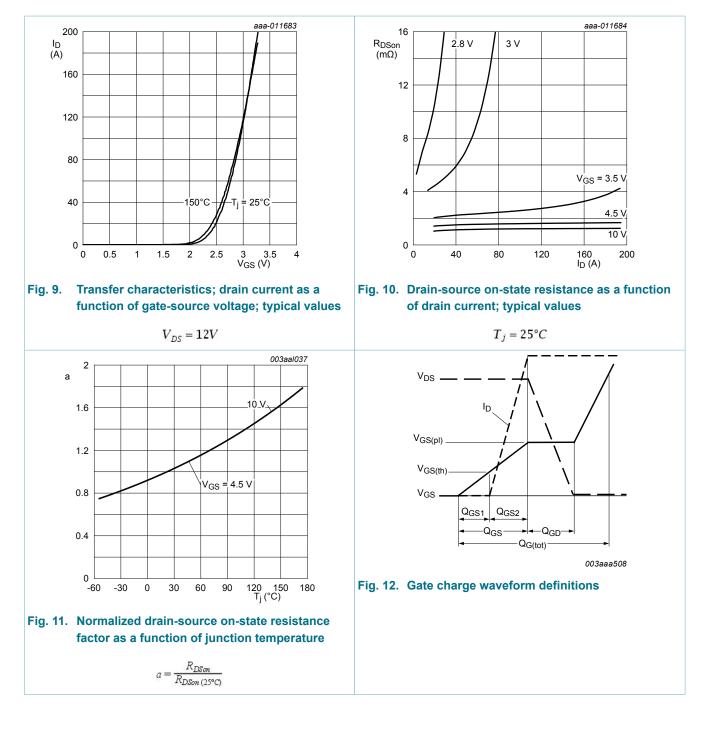
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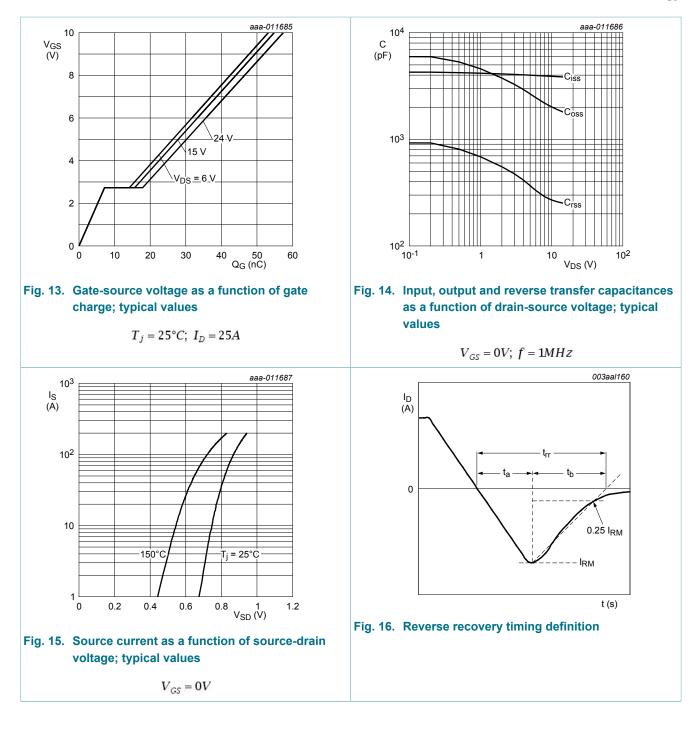
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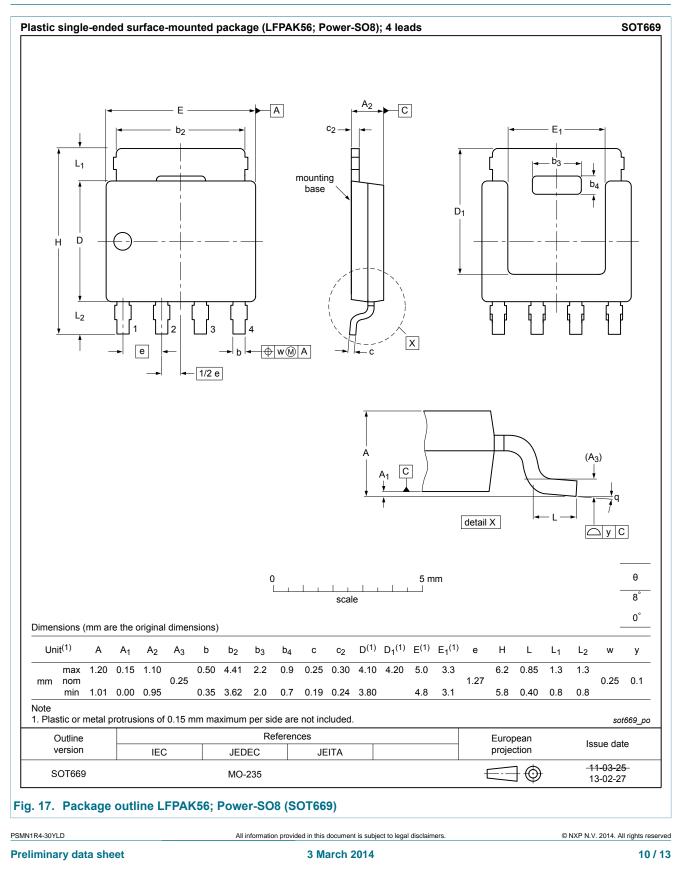


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N-channel 30 V, 1.4 mΩ logic level MOSFET in LFPAK56 using NextPowerS3 Technology

### 11. Package outline



#### N-channel 30 V, 1.4 mΩ logic level MOSFET in LFPAK56 using NextPowerS3 Technology

### 12. Legal information

#### 12.1 Data sheet status

Document status [1][2]	Product status [ <u>3]</u>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

 The term 'short data sheet' is explained in section "Definitions".
 The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <u>http://www.nxp.com</u>.

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